Erratum

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On-line coupling of atomic spectrometry and ion chromatography with time resolved registration as a new tool for ultra trace analysis in refractory metals

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In Table 3 on page 549 the column headings were unfortunately omitted. The entire table is printed correctly below.

Table 3. Analytical wavelengths of the ICP-spectrometer and matrix interference coefficients (ic_{analyte}) for Mo (according to Mo 202.032 nm) and W (according to the interference signal at the Se 196.09 nm line). The peak area calibration factor f_A was 3.03 dig/ng for Mo and 0.069 dig/ng for W. All data were evaluated with 1.85 ml/min sample flow rate and 10 s integration time. The signal to background ratios I_n/I_b and the estimated L.D. were calculated in the way described in [18]

Line	Grating grooves/mm	I_n/I_b	Estimated d.l. [ppb]	Mo ic_{analyte} [10^{-3} dig · ng $^{-1}$]	W ic_{analyte} [10^{-3} dig · ng $^{-1}$]
Ag 328.068 nm	3600	47.4	6.3	0.3	0.64
Al 396.152 nm	3600	11.8	25.5	114	1.0
Al 2308.215 nm	3600	6.8	43.9	28.1	12.7
Ba 455.404 nm	2400	199	1.5	0.067	0.44
Be 313.042 nm	3600	1570	0.2	0.12	0.3
Ca 317.933 nm	3600	27.5	11	1.4	81.3
Cd 226.502 nm	3600	8.1	37.2	0.52	6.2
Co 228.616 nm	3600	5.6	53.2	0.25	18.6
Cr 267.716 nm	3600	22.2	13.5	0.33	16
Cu 324.754 nm	3600	70.5	4.3	1.4	1.1
Fe 259.940 nm	3600	37.4	8	0.59	5.1
K 766.490 nm	2400	2.6	115	0.14	3.5
Mg 279.553 nm	3600	1220	0.2	0.07	1.1
Mn 257.610 nm	3600	293	1	0.24	178
Mo 202.032 nm	3600	6.3	47.6	3025	—
Na 589.592 nm	2400	6.5	46	3.95	0.9
Ni 231.603 nm	3600	11.9	25.2	0.17	3.9
Pb 220.351 nm	3600	10.8	27.5	0.22	11.3
Sc 361.384 nm	2400	72.5	4.1	0.48	46.6
Ti 334.940 nm	3600	235	1.3	0.16	12.6
Tl 190.860 nm	3600	4.1	74	0.8	67.4
W 196.09 nm ^a	3600	0.17	169 ppm	—	69
Zn 213.856 nm	3600	37.1	8.1	0.28	10.2
Ar 430.01 nm	2400	—	—	—	—

^a As monitor for W the interference of the W 196.149 nm line at the Se 196.09 nm line was used, the signal to background ratio was measured with a 1000 ppm W solution